PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:	10/701,332)		
Filed:	November 4, 2003)	Conf. No.:	5874
Title:	A Novel BISR Mode to Test)		
	the Redundant Elements and)		
	Regular Functional Memory)		
	to Avoid Test Escapes)		
)		
Inventor:	Ghasi R. Agrawal et al.)		
)		
Art Unit:	2117)		
)		
Examiner:	Steve N. Nguyen)		
)		
Atty. Ref:	03-1343)		

RESPONSE TO THE OFFICE ACTION MAILED OCTOBER 26, 2009

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed October 26, 2009, kindly enter the following amendments and consider the following remarks toward reconsideration of the present application.